

Design for Micro & Nano Manufacture (DfMM) News



web page: <http://www.patent-dfmm.org>

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The NoE Patent-DfMM aims to establish a collaborative team to provide European industry with support in the field of "design for micro nano manufacture" to ensure that problems affecting the manufacture and reliability of products based on micro nano technologies (MNT) can be addressed before prototype and pre-production.

PATENT-DfMM and INTEGRAMplus to present/exhibit at CEMMNT Launch Event, 2 May, Loughborough, UK

The Centre of Excellence in Metrology for Micro and Nano Technologies (CEMMNT) celebrates its official launch on Wednesday, 2 May 2007, at the Systems Engineering Innovation Centre (SEIC) in Loughborough, UK. CEMMNT provides industry with open access to measurement and characterisation techniques and expertise. A NEXUS sponsored FP7 brokerage session is integral to the event which aims to bring together over 150 major players in Micro and Nano Technology (MNT). The meeting includes technical presentations, panel discussions, an exhibition and ample networking opportunities.

More information: www.cemmnt.co.uk/events.html

PATENT-DfMM / NEXUS Workshop on Design for Reliability and Manufacturability in MNT, 24 Apr 07, Stresa, Italy (in conjunction with DTIP 25-27 Apr 2007)

This workshop builds on industry experience in microsystems' manufacturing as discussed within the MEMS Industry Group METRIC workshops and NEXUS Methodology Working Group meetings. Main emphasis will be on reliability and test problems, where design methodologies can lead to significant improvements. The workshop will discuss how to leverage the design, reliability and test communities over the coming years for the benefit of European competitiveness; this might include the need for new European and International collaborative initiatives. In addition, further industry demand for advances in Design, Reliability and Test capability will be addressed.

The Venue: Regina Palace Hotel - Stresa, Lago Maggiore, Italy

<http://tima.imag.fr/conferences/dtip/DTIP2007/HotelRegistrationForm.html>

Registration fee: €120 (including coffee breaks and lunch on 24 April); For registrations after 5 April: €160.

Please register for this 1 day Workshop on Design for Micro & Nano Manufacture through the DTIP registration form at http://tima.imag.fr/conferences/dtip/DTIP2007/Registration_Fee.pdf

Hotel and venue information is also available from <http://tima.imag.fr/conferences/dtip>

DTIP (25 - 27 April)

DTIP is the symposium on Design, Test, Integration and Packaging of MEMS and MOEMS. The goal of DTIP is to provide a forum for in-depth investigations and interdisciplinary discussions involving design, modelling, testing, micromachining, microfabrication, integration and packaging of structures, devices, and systems. More information at <http://tima.imag.fr/conferences/dtip>

PATENT-DfMM and NEXUS are also co-organising a special session within DTIP on "**Opportunities for Cooperative R&D**" (25 Apr) and a panel discussion on "Design for Reliability and Test of Microsystems" (26 Apr). In the panel industrial microsystems manufacturers will present the way they deal with reliability and test issues currently and what their main challenges are. Also results from the Workshop on 24 April will

be summarised.

More information will be published at www.patent-dfmm.org
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PATENT-DfMM to showcase its (planned) Services at Europractice Exhibitions

Having joined the Europractice Family of Microsystems Service Projects in 2006, the "Design for Micro & Nano Manufacture Network" is taking part in this year's Europractice booths at Smart Systems Integration (Paris, France, 27-28 Mar 2007) and Hannover Fair (Hannover, Germany, 16-20 April 2007). At Hannover Fair the Europractice booth will be located within the IVAM Microtechnology area in exhibit hall 015, D34.

PATENT-DfMM will showcase its services to industry, some of which already on offer, others still under development:

- ▶ ETS - Embedded Test Solutions for MNT-based Systems
- ▶ HUMS - Health and Usage Monitoring Microsystems
- ▶ Eumirel - European Microsystems Reliability Service Cluster
- ▶ MEF - Service Cluster Micro-Electronic Fluidics
- ▶ Systems Design and Design Support for MNT-based Systems

PATENT-DfMM project partners are keen on discussing industry requirements and needs for such services with potential users. As not all specialists will be available at the exhibition for the complete week, it is advised to make appointments prior to the exhibition.

PATENT-DfMM is also planning to be available for discussion and inquiries at the following events:

- ▶ AMAA 2007 - Advanced Microsystems for Automotive Applications (Berlin, Germany, 9-10 May 2007)
- ▶ METRIC (Pittsburgh, USA, 14-16 May 2007)
- ▶ MINOS Brokerage Event (Bucharest, Romania, 23-24 May 2007)
- ▶ Transducers / Eurosensors (Lyon, 11-14 Jun 2007)

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MEMUNITY Workshop on March 6 in Grenoble, France - Presentations available

MEMUNITY likes to thank all speakers and attendees for a successful workshop in Grenoble at Minatec. The high number of registrations - the workshop was fully booked - demonstrates the growing interest in the MEMS field. The one-day workshop consisted of experiences, solutions and measurements all around MEMS presented via talks and a setup of SUSS and Polytec equipment and was concluded by a visit to different CEA-LETI and Minatec facilities. All presentations held during the workshop are available free of charge within MEMUNITY's member area: www.memunity.org.

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